

Notice of References Cited	Application/Control No. 10/806,420		Applicant(s)/Patent Under Reexamination SHIN ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0057657 A1	05-2002	LA PORTA et al.	370/331
*	B	US-6,496,704 B2	12-2002	Yuan, Ruixi	455/466
*	C	US-2002/0191627 A1	12-2002	Subbiah et al.	370/428
*	D	US-2003/0161287 A1	08-2003	Venkitaraman et al.	370/338
*	E	US-2003/0225912 A1	12-2003	Takeda et al.	709/246
*	F	US-2004/0063402 A1	04-2004	Takeda et al.	455/041.1
*	G	US-2004/0100951 A1	05-2004	O'Neill, Alan	370/389
*	H	US-2004/0105420 A1	06-2004	Takeda et al.	370/349
*	I	US-2004/0114554 A1	06-2004	Okajima et al.	370/329
*	J	US-2004/0137888 A1	07-2004	Ohki, Masahiro	455/417
*	K	US-2004/0205211 A1	10-2004	Takeda et al.	709/230
*	L	US-2004/0203740 A1	10-2004	Won et al.	455/426.1
*	M	US-2004/0205235 A1	10-2004	Matsuhira, Naoki	709/238

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0258008 A1	12-2004	Inoue et al.	370/312
*	B	US-2005/0020265 A1	01-2005	Funabiki et al.	455/436
*	C	US-6,957,262 B2	10-2005	Kimura et al.	709/227
*	D	US-2006/0013170 A1	01-2006	Shin et al.	370/338
*	E	US-2006/0062214 A1	03-2006	Ng et al.	370/389
*	F	US-7,039,035 B2	05-2006	Droms et al.	370/338
*	G	US-7,123,599 B2	10-2006	Yano et al.	370/331
*	H	US-2007/0005971 A1	01-2007	Leung et al.	713/171
*	I	US-7,215,668 B2	05-2007	Saito, Shin	370/392
*	J	US-7,251,238 B2	07-2007	Joshi et al.	370/338
*	K	US-7,453,842 B2	11-2008	Yamamoto, Junji	370/328
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
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	Q					
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